Advances in SI-traceable Detector Standards for the Reflected Solar Region

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Development of Transfer and Working Standard Detectors Traceable to Cryogenic Radiometers

- Low-noise Pyroelectric Detectors
 - Calibrate in the Vis-NIR and use in the SWIR
- Replace broadly tunable SIRCUS lasers in transferring scale(s) against NIST cryogenic radiometers
 - Supercontinuum source-pumped Laser Line Tunable Filter
 - kHz repetition rate OPO
- Develop Irradiance-Mode ACR
- Working Standard Spectrographs (Si range)

Motivation

The SIRCUS facility has demonstrated that moving from source-based scales traceable to primary standard blackbodies to detector-based scales traceable to low temperature electric substitution cryogenic radiometers offer opportunities to reduce the uncertainties in disseminated standards.



Example: Radiance Temperature Measurements

Expanded Uncertainties (*k*=2) ≈ 0.08 % Yoon, H. W., et al., Appl. Opt. 46, 2870 (2007)

Background: Spectrographs as Working Standards

Came out of work at the Whipple Observatory, Mt. Hopkins, Amado AZ*



Spectrographs as Candidate Working Standards Came out of work at the Whipple Observatory, Mt. Hopkins, Amado AZ*

Spectrograph Characteristics

- CCD-based fiber-fed slit spectrograph
- 380 nm to 1040 nm, 4 nm resolution
- Temperature-stabilized CCD

from 11/2012 - 6/2014

Deployed to Mt. Hopkins and returned to NIST several times

Event where water spilled onto the instrument – and it was left outside for a while to dry

Radiometric Stability v an FEL-lamp

Calibration setup not maintained; reproduced for each measurement.



Repeatability of Fiber insertion into spectrograph

Fiber plug-in repeatability Mt. Hopkins Stability Data × initial 1.006 unplug and replug 1 1.006 unplug and replug 2 1.004 replug clockwise replug ccw 1.004 1.002 Ratio to Mean 1.002 **Ratio to Mean** 1.000 1 0.998 0.998 0.996 0.996 0.994 0.994 500 700 900 300 1100 Wavelength [nm] 400 800 900 500 600 700 1000 Wavelength [nm]

Most of the observed variability from fiber insertion into the spectrograph

Spectrograph Characterizations to evaluate its potential for use as a Working standard

- Absolute spectral responsivity
- Wavelength scale
- Stability
- Stray light correction
- Bandpass correction
- Linearity
- Temperature dependence

(SIRCUS) (SIRCUS) (FEL lamps) (SIRCUS) (SIRCUS)

Absolute Calibration of a Reference Spectrograph

FEL-Lamp calibration often the single largest source of uncertainty Solution: Map out the Single Pixel Responsivity of every pixel using SIRCUS



Wavelength scale Comparison between SIRCUS and the Instrument Vendor

Vendor Wavelength uncertainty: ±0.5 nm





Stability measurements: Weekly measurements with FEL lamp over 2 mos.





Stability measurements: E head



Measurements continue on a monthly basis for 6 mos. to a year.

Stray Light Spectral Response of Pixel 240



Stray light correction algorithm

 $S_{meas} = [I+D]S_{IB}$

Stray Light Distribution Function, D Describes the scattering properties of the spectrograph



Y. Zong, et al., Simple spectral stray light correction method for array spectroradiometers, Appl. Opt. 45(6), 1111 – 1119 (2006).

Example Results of Stray Light Correction $S_{IB} = [I+D]^{-1}S_{meas} = C \cdot S_{meas}$







Stray Light Corrected Marine Optical Buoy (MOBY) Response Impact on MODIS Imagery: Chlorophyll-a concentration Courtesy of Dennis K. Clark, NOAA (ret.)

Tent

Assembly & System Calibration of MOBY

Sea Van

Lasers installed Cal of MOS



Arms fiber-optic coupled to MOS



After Correction



Before Correction



Log of Total Chlorophyll-a

Log of Total Chlorophyll-a

Developing Protocols to characterize and calibrate Spectrographs Validate Instrument Responsivity in the field based on working standard detectors

Monochromatic Light from Supercontinuum Source-pumped Laser Line Tunable Filter

Vis-NIR Detector-based Scale held on Si photodiodes



Validation Source SC source-pumped LLTF

- LLTF output fibercoupled to a 2" integrating sphere equipped with a monitor photodiode
- Test spectrographs about 30 cm away
- Spectrograph integrates for 10 s
- Measurements from 450 nm to 1000 nm every 10 nm for 5 consecutive days.

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Output of SC-LLTF source

LLTF-Based Stability

Measurements made on 5 consecutive days



Wavelength [nm]

Uncertainty Estimate

Component	Uncertainty (k=1) %	Uncertainty (k=1) %
Absolute responsivity	0.1	0.2
Wavelength	<0.1	
Stability	0.02	0.02
Stray light	<0.01	
Field Validation	0.05	0.1
Other	0.1	0.1
Total	0.15	0.245

May be possible to achieve 0.5 % (k=2) uncertainties for A Working Standard Spectrograph

Implications: Irradiance scale

Uncertainty in NIST Irradiance Scale Disseminated Standards (FEL lamps)



Spectrograph uncertainty target: 0.5 % k=2 or less over full spectral region

H. Yoon and Charles Gibson, <u>Spectral Irradiance Calibrations</u>, NIST Special Publ. 250-89 (July 2011).

Implications: Radiance Scale

Potential impact on lamp-Illuminated Integrating Sphere uncertainties

- From Butler *et al.*¹ the uncertainty in disseminated <u>radiance scales</u> are 2% to 3% in the Vis/NIR (silicon) region.
 - Includes uncertainties in the reference radiance meters (not negligible)
- Uncertainties in a Working Standard Spectrograph on the order of 0.2 % to 0.3 % (k=1) or less



Using a Working Standard Spectrograph *in situ* (at the time of measurement) may reduce the uncertainties in the disseminated Radiance Scale an order of magnitude, to a level that meets or exceeds most satellite sensor laboratory calibration uncertainty requirements.

Summary

- Demonstrated the possibility of developing Working Standard Spectrographs in the silicon range
 - Expanded (k=2) uncertainty 0.5 %
- Demonstrated the field calibration/validation source based in single element working standard detectors, in this case Si
 - With a very limited set of measurements, validated the spectrograph stability with an uncertainty less than 0.1 %
- Explored the possibility of improving the resolution of a spectrograph beyond the single pixel responsivity limit
 - To the pixel-to-pixel spacing

Future Direction

Bandpass Correction

Is it possible to have a spectral resolution below the SPR limit?



LLTF Source spectral distribution



LLTF source spectral distribution measured by spectrograph ~ 4.5 nm 5 Signal Normalized by Monitor 2016/06/20 2016/06/21 2016/06/22 2016/06/23 2016/06/24 3 2 1 535 537 539 541 543 545 547

Wavelength [nm]

Bandpass Correction Algorithm

Measurement Equation after Stray Light Correction: In-Band Responsivity collapsed along the diagonal.

$$\begin{bmatrix} s_1 \\ s_2 \\ s_3 \\ s_n \end{bmatrix} = \begin{bmatrix} r_{11} & 0 & 0 & 0 \\ 0 & r_{22} & 0 & 0 \\ 0 & 0 & r_{33} & 0 \\ 0 & 0 & 0 & r_{nn} \end{bmatrix} \cdot \begin{bmatrix} e_1 \\ e_2 \\ e_3 \\ e_{nn} \end{bmatrix}$$

We have thrown away information about the in-band responsivity.

What if we put that information back into the Measurement Equation?



In Band-Expanded Measurement Equation after Stray Light Correction

 $S = R \cdot e$



Knowing **S** and **R**, can we solve the system of linear equations for **e**? What does **e** look like?

Proof-of-Principle Simulations

Source Distribution Assume a Gaussian source distribution $\sigma=1$

FWHM = $2.35^*\sigma$

Single Pixel Responsivity Assume a Gaussian source distribution $\sigma=3$

FWHM = $7.05^*\sigma$



Simulation:

Look at the achievable resolution

Resolution achievable may be ~equal to the pixel-to-pixel spacing



80

100

0.00E+00

-2.00E-02

20

40

Source D Truth Sig Calc Source D Calc

60